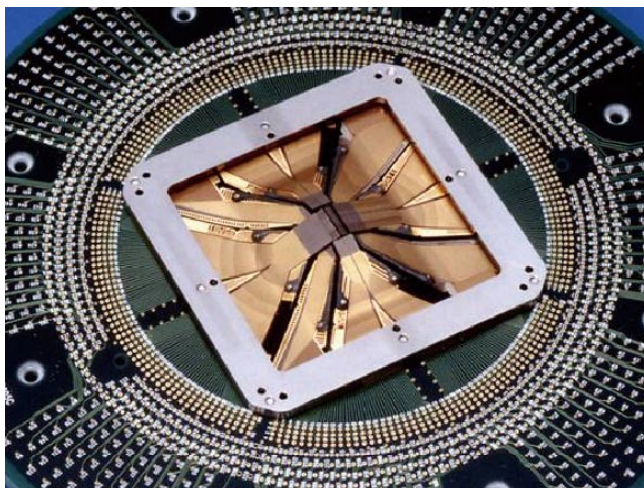
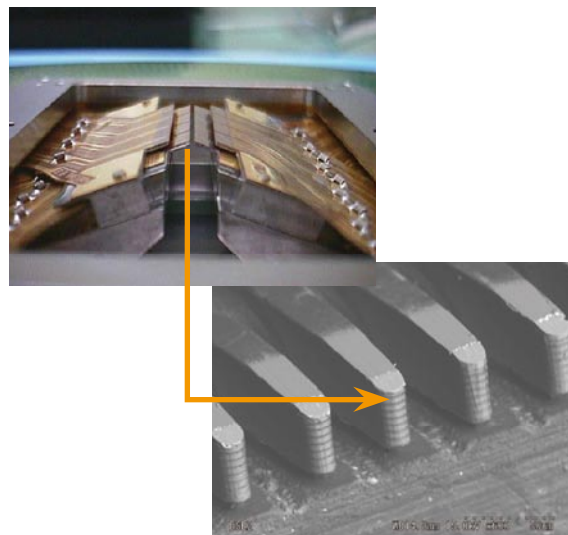


Yokowo P-4 Probe Card

(YP4 series)



Yokowo P-4 Probe Card



Applications

- YP4(MEMS)method is available for Peripheral electrode array, which pitch size is more than 30 μ m.

Features

- Available for 10GHz On-Wafer testing.
- Providing appropriate pattern design by simulating in the electromagnetic field.
- Light turned spring force helps to meet CUP(Circuit Under Pad) device test.
- Enable to install RF pattern of matching circuit near the contact point.
- Available for Peripheral Min Pitch 30 μ m.

Specifications

Insertion Loss	$\geq -1\text{dB}@10\text{GHz}$
Return Loss	$\leq -10\text{dB DC}\sim 10\text{GHz}$
Isolation	$< -50\text{dB}@DC\sim 12\text{GHz}$
Current Carrying Capablility	200mA / pad
Contact Resistance	1 Ω
Pin Force	2g / Pin(AL pad)
Pitch(peripheral)	Min 30 μ m